

STD4LNK60Z STF4LNK60Z

N-channel 600 V, 2.2 Ω, 3.3 A, TO-220FP, DPAK Zener-protected SuperMESH[™] Power MOSFET

Preliminary Data

Features

Туре	V _{DSS}	R _{DS(on)} max	۱ _D	Pw
STD4LNK60Z	600 V	< 2.7 Ω	3.3 A	70 W
STF4LNK60Z	600 V	< 2.7 Ω	3.3 A	25 W

- Extremely high dv/dt capability
- 100% avalanche tested
- Gate charge minimized
- Very low intrinsic capacitances
- Improved ESD capability

Application

Switching applications

Description

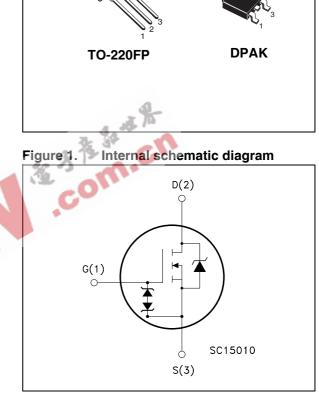
The SuperMESH[™] series is obtained through an extreme optimization of ST's well established strip-based PowerMESH[™] layout. In addition to pushing on-resistance significantly down, special care is taken to ensure a very good dv/dt capability for the most demanding applications. Such series complements ST's full range of high voltage Power MOSFETs including revolutionary MDmesh[™] products.

Table 1. Device summary

Order codes	Marking	Package	Packaging
STD4LNK60Z	4LNK60Z	DPAK	Tape and reel
STF4LNK60Z	4LNK60Z	TO-220FP	Tube







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Electrical ratings 1

	2	Va		
Symbol	Parameter	TO-220FP	DPAK	– Unit
V _{DS}	Drain-source voltage (V _{GS} = 0)	60	00	V
V _{GS}	Gate-source voltage	±	30	V
۱ _D	Drain current (continuous) at $T_C = 25 \degree C$	3.3 ⁽¹⁾	3.3	А
۱ _D	Drain current (continuous) at T _C = 100 °C	2 ⁽¹⁾	2	А
I _{DM}	Drain current (pulsed)	13.2 ⁽¹⁾	13.2	А
P _{TOT}	Total dissipation at $T_{C} = 25 \text{ °C}$	25	70	W
	Derating factor	0.2	0.56	W/°C
V _{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink (t=1 s;T _C =25 °C)	2500		v
T _j T _{stg}	Operating junction temperature Storage temperature	-55 to	o 150	°C
1. Limited by Table 3.	package Thermal data			

Table 2. Absolute maximum ratings

Thermal data Table 3.

Symbol	Parameter	Val	Unit	
	Parameter	TO-220FP	DPAK	Unit
R _{thj-case}	Thermal resistance junction-case	5	1.79	°C/W
R _{thj-pcb}	Thermal resistance junction-pcb ⁽¹⁾		50	°C/W
R _{thj-amb}	Thermal resistance junction-amb	62.5		°C/W
Τ _Ι	Maximum lead temperature for soldering purpose	g 300		°C

1. Minimum footprint

Table 4. Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AR}	Avalanche current, repetitive or not repetitive (pulse width limited by Tjmax)	TBD	A
E _{AS}	Single pulse avalanche energy ⁽¹⁾	TBD	mJ

1. Starting Tj = 25 °C, $I_D = I_{AR}$, $V_{DD} = 50$ V



Electrical characteristics 2

(T_{CASE}=25 °C unless otherwise specified)

	On/on states					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 1 mA, V _{GS} = 0	600			۷
I _{DSS}	Zero gate voltage drain current ($V_{GS} = 0$)	V_{DS} = Max rating, V_{DS} = Max rating,Tc=125 °C			1 50	μΑ μΑ
I _{GSS}	Gate body leakage current (V _{DS} = 0)	$V_{GS} = \pm 30 V$			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 50 \ \mu A$	2	3	4	V
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10 V, I _D = 2.7 A		2.2	2.7	Ω

Table 5. On/off states

Table 6. Dynamic

Table 6.	Dynamic	A A A	-			·
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} =25 V, f=1 MHz, V _{GS} =0		400 50 10		pF pF pF
C _{oss eq.}	Equivalent output capacitance	$V_{\rm DS}$ = 0 to 480 V, $V_{\rm GS}$ =0		44.4		pF
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V_{DD} = 480 V, I _D = 3.3 A V_{GS} = 10 V (see Figure 3)		14 TBD TBD		nC nC nC

Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on delay time Rise time	V_{DD} = 300 V, I _D = 3.3 A, R _G =4.7 Ω , V _{GS} =10 V (see Figure 2)		7.5 19.5		ns ns
t _{d(off)} t _f	Turn-off delay time Fall time	V_{DD} =300 V, I _D = 3.3 A, R _G =4.7 Ω , V _{GS} = 10 V (see Figure 2)		28 24		ns ns



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} ⁽¹⁾	Source-drain current Source-drain current (pulsed)				3.3 13.2	A A
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 3.3 A, V _{GS} =0			TBD	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} = 3.3 A, di/dt = 100 A/μs, V _{DD} =480 V, Tj=150°C (<i>see Figure 7</i>)		TBD TBD TBD		ns nC A

Table 8. Source drain diode

1. Pulse width limited by package

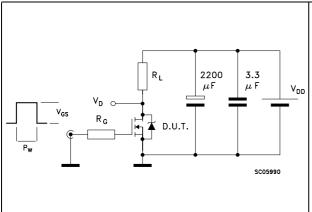
2. Pulsed: pulse duration = 300μ s, duty cycle 1.5%





3 Test circuits

Figure 2. Switching times test circuit for resistive load



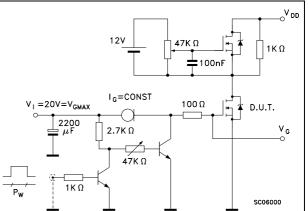


Figure 4. Test circuit for inductive load switching and diode recovery times



JUIJ

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Switching time waveform

2200

 μ F

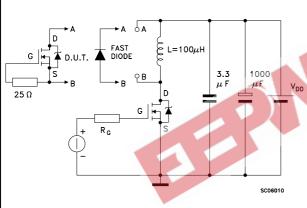
3.3

 μ F

SC05970

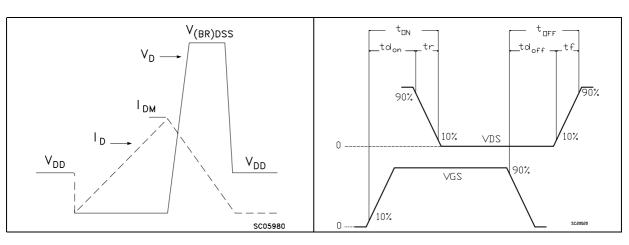
 V_{DD}

57





I_D



٧

Pw

Figure 7.

4 Package mechanical data

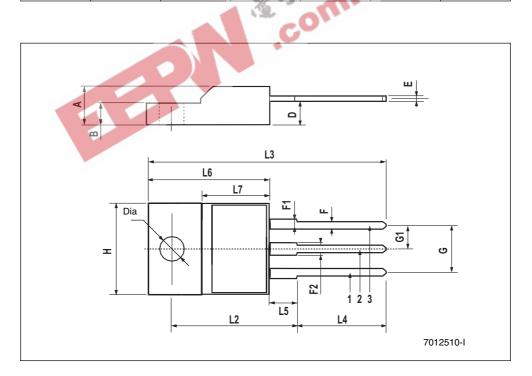
In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: *www.st.com*





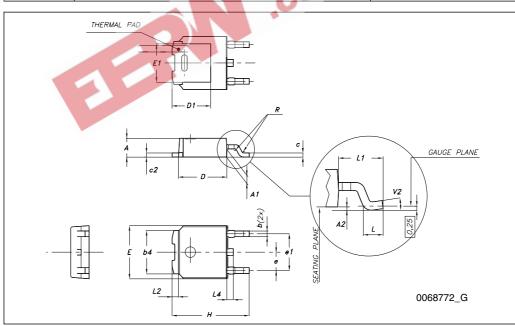
Dim.		mm.			inch	
Dini.	Min.	Тур	Max.	Min.	Тур.	Max.
А	4.40		4.60	0.173		0.181
В	2.5		2.7	0.098		0.106
D	2.5		2.75	0.098		0.108
E	0.45		0.70	0.017		0.027
F	0.75		1.00	0.030		0.039
F1	1.15		1.50	0.045		0.067
F2	1.15		1.50	0.045		0.067
G	4.95		5.20	0.195		0.204
G1	2.40		2.70	0.094		0.106
Н	10		10.40	0.393		0.409
L2		16			0.630	
L3	28.6		30.6	1.126		1.204
L4	9.80		10.60	0.385		0.417
L5	2.9		3.6	0.114		0.141
L6	15.90		16.40	0.626		0.645
L7	9		9.30	0.354		0.366





Γ

		(DPAK) mechanical data			
DIM.	mm.				
Diwi.	min.	typ	max.		
A	2.20		2.40		
A1	0.90		1.10		
A2	0.03		0.23		
b	0.64		0.90		
b4	5.20		5.40		
с	0.45		0.60		
c2	0.48		0.60		
D	6.00		6.20		
D1		5.10			
E	6.40		6.60		
E1		4.70			
е		2.28			
e1	4.40		4.60		
Н	9.35	0	10.10		
L	1	2 1	P		
L1		2.80			
L2		0.80			
L4	0.60		1		
R		0.20			
V2	0 °		8 °		



TO-252 (DPAK) mechanical data



5 Revision history

Table 9.Document revision history

Date	Revision	Changes
24-Jul-2008	1	Initial release.





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